



650V Super-junction Power MOSFET

Description

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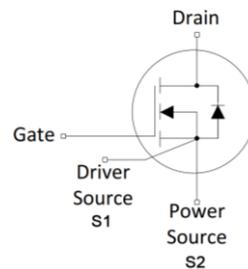
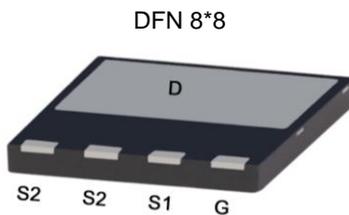
Super-junction power MOSFET is a revolutionary technology for high voltage power MOSFETs, designed according to the SJ principle. The Multi-EPI SJ MOSFET provide an extremely low switching, communication and conduction losses device with highest robustness make especially resonant switching applications more reliable, more efficient, lighter and cooler,also fits the industrial grade applications,like AC-DC SMPS requirements for PFC, AC/DC power conversion, designed by Wuxi Unigroup Microelectronics Company.

Features

- Very low FOM $R_{DS(on)} \times Q_g$
- 100% avalanche tested
- Easy to use/drive
- RoHS compliant

Applications

- Switch Mode Power Supply (SMPS)
- Uninterruptible Power Supply (UPS)
- Power Factor Correction (PFC)
- Charger



Device Marking and Package Information

Device	Package	Marking
TPG65R125MH	DFN 8*8	65R125M

Key Performance Parameters

Parameter	Value	Unit
$V_{DS} @ T_{j,max}$	700	V
$R_{DS(on),max}$	0.125	Ω
$Q_{g,typ}$	57	nC
I_D	30	A
$I_{D,pulse}$	90	A
$E_{OSS} @ 400V$	6.54	μJ
Body Diode di_f/dt	500	A/ μs



Absolute Maximum Ratings $T_C = 25^\circ\text{C}$, unless otherwise noted				
Parameter		Symbol	Value	Unit
Continuous Drain Current	$T_C = 25^\circ\text{C}$	I_D	30	A
	$T_C = 100^\circ\text{C}$		18	
Pulsed Drain Current (note1)		$I_{D,pulse}$	90	A
Gate-Source Voltage		V_{GSS}	± 30	V
Single Pulse Avalanche Energy (note2)		E_{AS}	636	mJ
Repetitive Avalanche Energy (note2)		E_{AR}	0.96	mJ
Avalanche Current		I_{AR}	5.2	A
MOSFET dv/dt Ruggedness, $V_{DS} = 0 \dots 480\text{V}$		dv/dt	50	V/ns
Power Dissipation For DFN 8*8		P_D	219	W
Continuous Diode Forward Current		I_S	26	A
Diode Pulsed Current (note1)		$I_{S,pulse}$	90	
Reverse Diode dv/dt (note3)		dv/dt	15	V/ns
Maximum Diode Commutation Speed (note3)		di/dt	500	A/ μs
Operating Junction and Storage Temperature Range		T_J, T_{stg}	-55~+150	$^\circ\text{C}$

Thermal Resistance For DFN 8*8			
Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-Case	R_{thJC}	0.57	$^\circ\text{C}/\text{W}$
Thermal Resistance, Junction-to-Ambient	R_{thJA}	62	



Electrical Characteristics $T_J = 25^\circ\text{C}$, unless otherwise noted						
Parameter	Symbol	Test Conditions	Value			Unit
			Min.	Typ.	Max.	
Static Characteristics						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	650	--	--	V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 650V, V_{GS} = 0V, T_J = 25^\circ\text{C}$	--	--	1	μA
		$V_{DS} = 650V, V_{GS} = 0V, T_J = 150^\circ\text{C}$	--	--	100	
Gate-Source Leakage Current	I_{GSS}	$V_{GS} = \pm 30V$	--	--	± 100	nA
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	2.5	--	4.5	V
Drain-Source On-State-Resistance	$R_{DS(on)}$	$V_{GS} = 10V, I_D = 15A$	--	0.116	0.125	Ω
Gate Resistance	R_G	$f = 1.0\text{MHz}$ open drain	--	1.5	--	Ω
Dynamic Characteristics						
Input Capacitance	C_{iss}	$V_{GS} = 0V,$ $V_{DS} = 100V,$ $f = 1.0\text{MHz}$	--	2393	--	μF
Output Capacitance	C_{oss}		--	90	--	
Reverse Transfer Capacitance	C_{rss}		--	4	--	
Total Gate Charge	Q_g	$V_{DD} = 520V, I_D = 30A,$ $V_{GS} = 10V$	--	57	--	nC
Gate-Source Charge	Q_{gs}		--	13	--	
Gate-Drain Charge	Q_{gd}		--	21	--	
Turn-on Delay Time	$t_{d(on)}$	$V_{DD} = 400V, I_D = 30A,$ $R_G = 25\Omega$	--	24	--	ns
Turn-on Rise Time	t_r		--	40	--	
Turn-off Delay Time	$t_{d(off)}$		--	191	--	
Turn-off Fall Time	t_f		--	73	--	
Drain-Source Body Diode Characteristics						
Body Diode Forward Voltage	V_{SD}	$T_J = 25^\circ\text{C}, I_{SD} = 15A, V_{GS} = 0V$	--	0.9	1.2	V
Reverse Recovery Time	t_{rr}	$V_R = 400V, I_F = I_S,$ $di_F/dt = 100A/\mu s$	--	486	--	ns
Reverse Recovery Charge	Q_{rr}		--	7.4	--	μC
Peak Reverse Recovery Current	I_{rrm}		--	30.6	--	A

Notes

1. Repetitive Rating: Pulse width limited by maximum junction temperature
2. $I_{AS} = 5.2A, V_{DD} = 50V, R_G = 25\Omega,$ Starting $T_J = 25^\circ\text{C}$
3. Identical low side and high side switch with identical R_G

Typical Characteristics $T_J = 25^\circ\text{C}$, unless otherwise noted

Figure 1. Output Characteristics

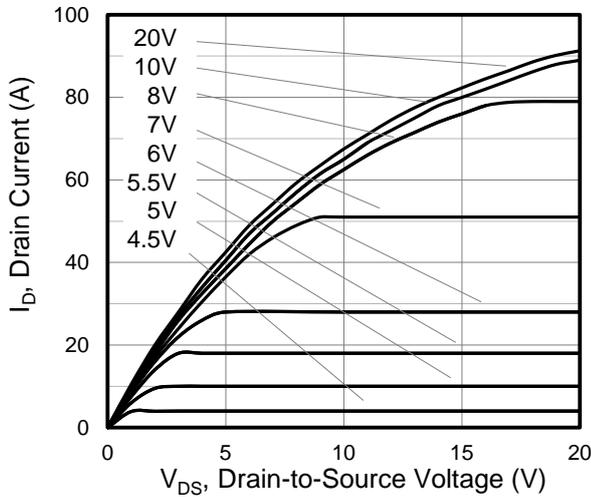


Figure 2. Transfer Characteristics

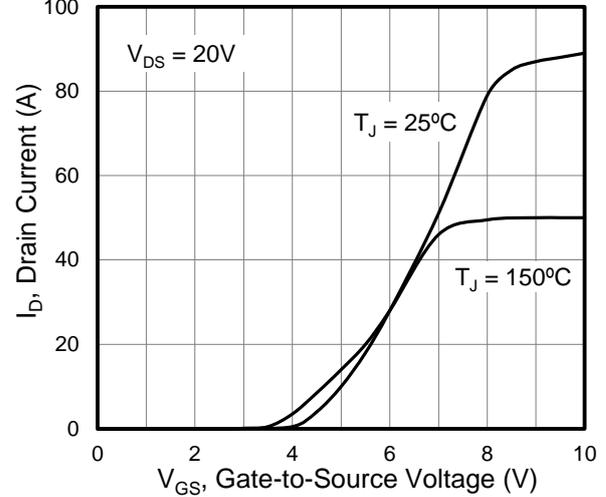


Figure 3. On-Resistance vs. Drain Current

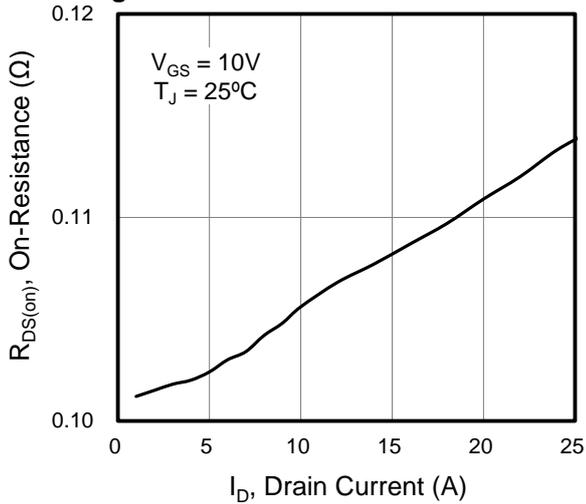


Figure 4. Capacitance

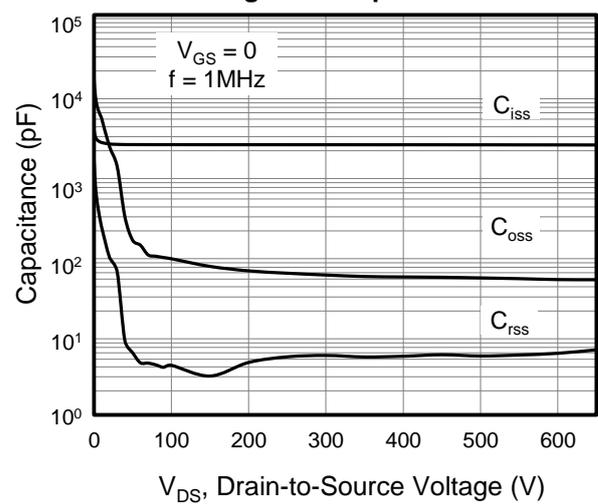


Figure 5. Gate Charge

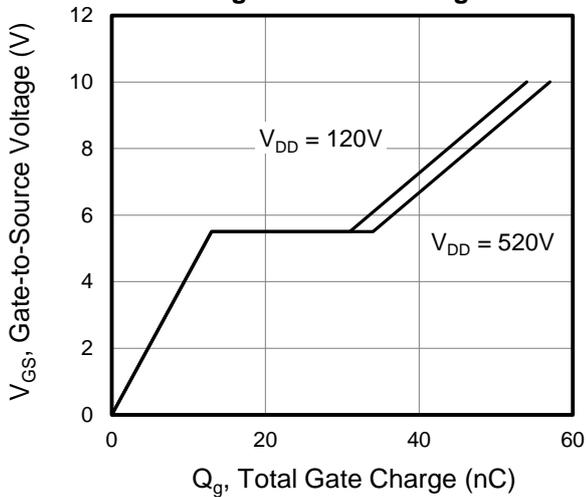
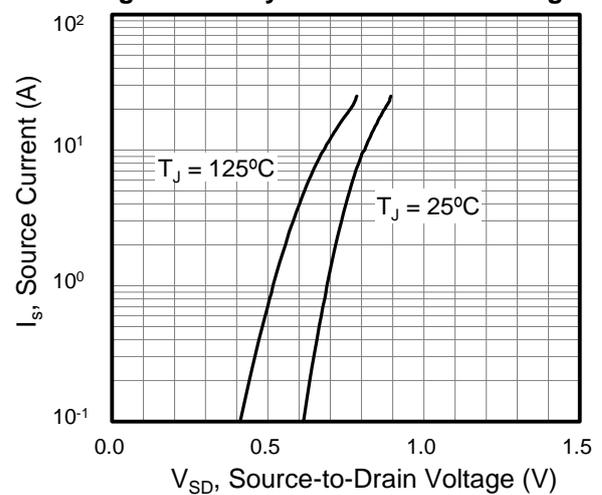


Figure 6. Body Diode Forward Voltage





Typical Characteristics $T_J = 25^\circ\text{C}$, unless otherwise noted

Figure 7. On-Resistance vs. Temperature

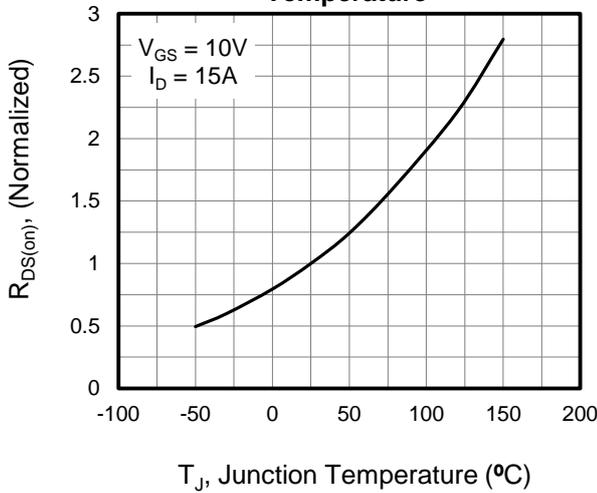


Figure 8. Breakdown voltage vs. Junction Temperature

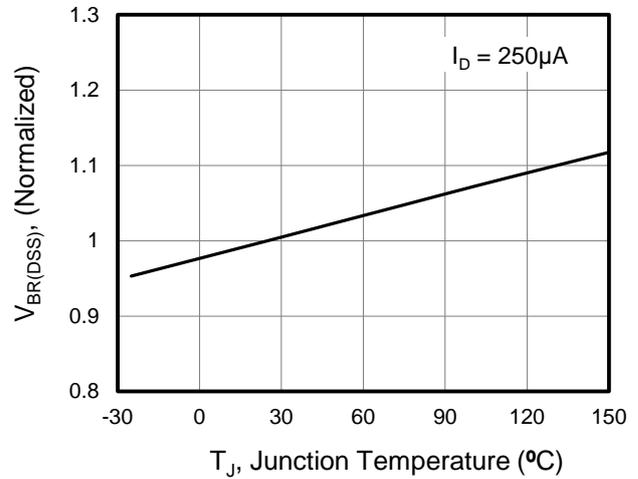


Figure 9. Transient Thermal Impedance For DFN 8*8

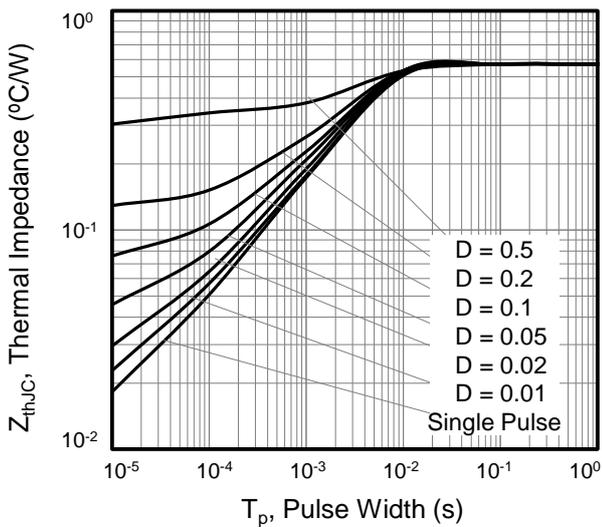


Figure 10. Safe Operation Area For DFN 8*8

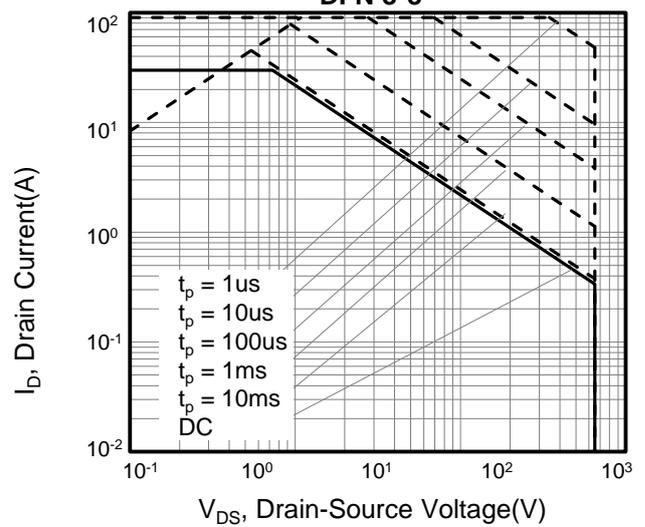


Figure 11. Typ. Coss Stored Energy

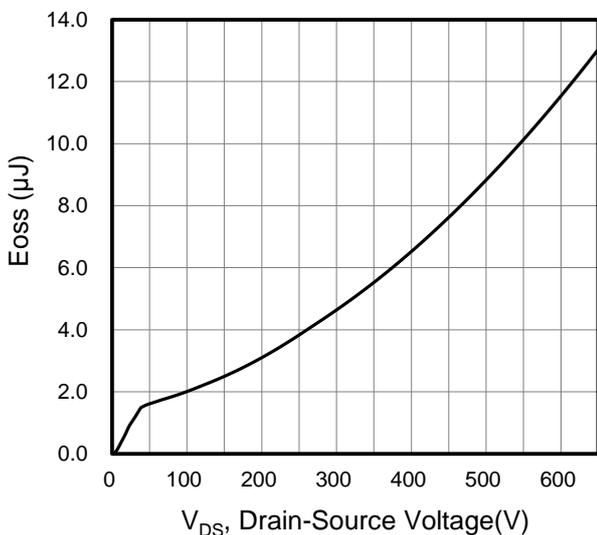




Figure A: Gate Charge Test Circuit and Waveform

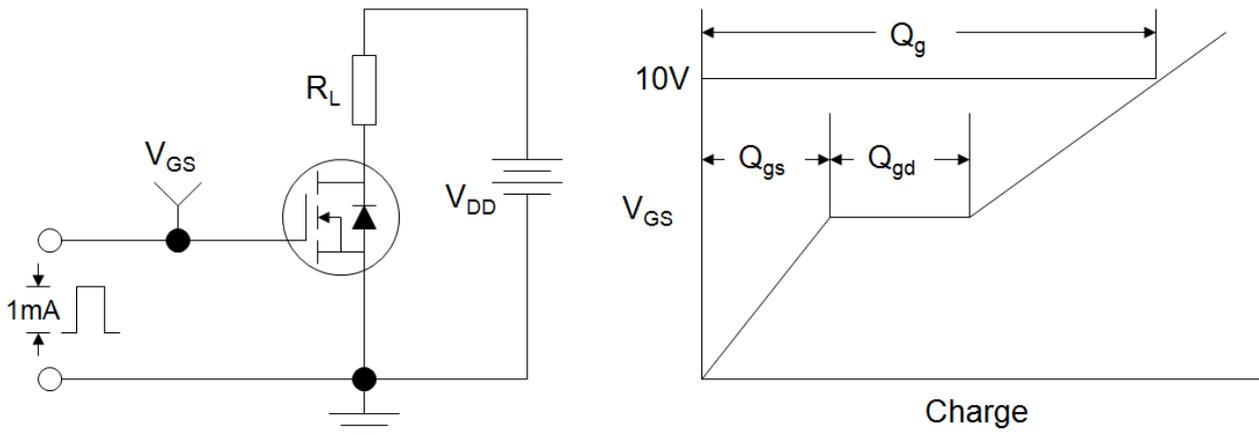


Figure B: Resistive Switching Test Circuit and Waveform

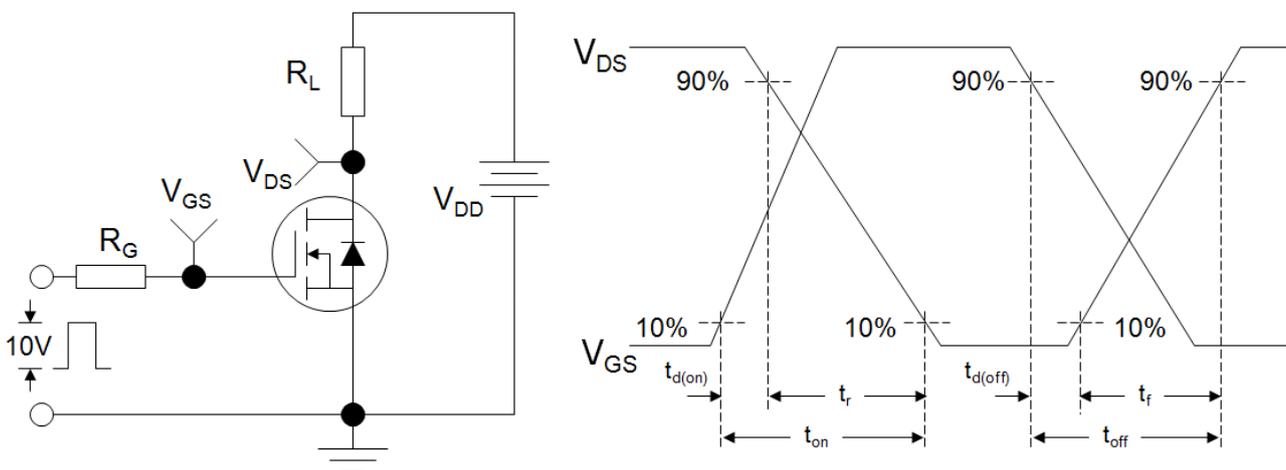
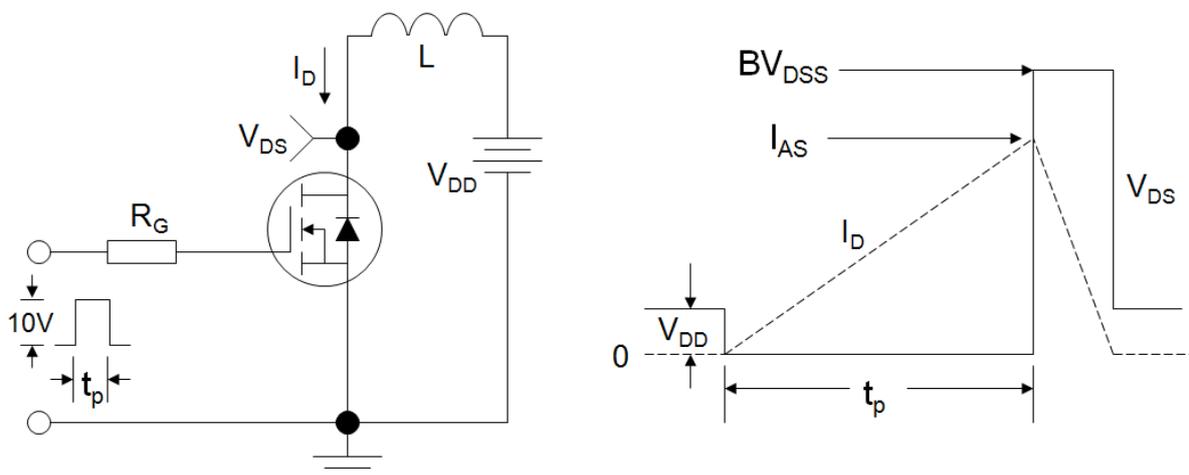
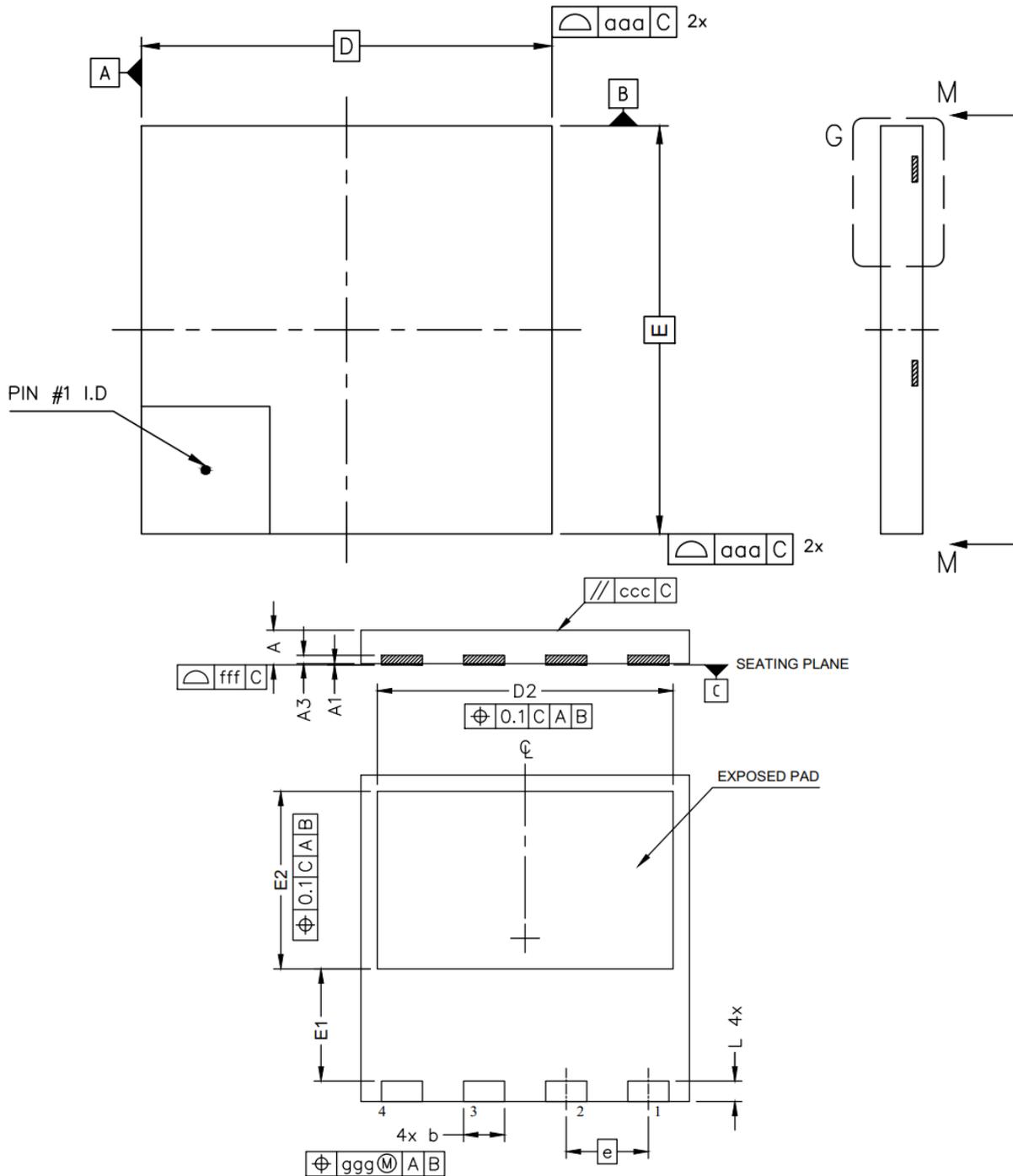


Figure C: Unclamped Inductive Switching Test Circuit and Waveform





DFN 8*8



Unit:mm				Unit:mm			
Symbol	Min.	Nom	Max.	Symbol	Min.	Nom	Max.
A	0.75	0.85	0.95	E2	4.25	4.35	4.45
A1	0.00	-	0.05	e	2.00 BSC		
A3	0.10	0.20	0.30	L	0.40	0.50	0.60
b	0.90	1.00	1.10	aaa	0.10		
D	7.90	8.00	8.10	ggg	0.05		
E	7.90	8.00	8.10	ccc	0.05		
D2	7.10	7.20	7.30	fff	0.05		
E1	2.65	2.75	2.85				



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